

ABSTRACT:

Method for inspecting an integrated circuit.

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The method for inspecting an integrated circuit comprising a plurality of sub-circuits includes the determination of the supply current into at least one of the sub-circuits. This supply current is determined, while the other sub-circuits are operational, by measuring the voltage over a segment of the supply line through which this supply current  
5 flows. This supply line contains no additional components to facilitate the measuring of the voltage.

Figure 3

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